Se	earch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/824,090	LIN ET AL.
Examiner	Art Unit
Biju Chandran	2835

SEARCHED				
Class	Subclass	Date	Examiner	
361	721	12/1/2005	BIC	
361	719	12/1/2005	bic	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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